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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	176
Number of Gates	36000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx24-2pqg208i

Figure 51	BG272	145
Figure 52	PG132	153
Figure 53	CQ172	158

2.4 Plastic Device Resources

Table 2 • Plastic Device Resources

Device	User I/Os											
	PLCC		PLCC		PQFP		PQFP		VQFP		TQFP	PBGA
	44-Pin	68-Pin	84-Pin	100-Pin	144-Pin	160-Pin	208-Pin	240-Pin	80-Pin	100-Pin	176-Pin	272-Pin
A40MX02	34	57	—	57	—	—	—	—	57	—	—	—
A40MX04	34	57	69	69	—	—	—	—	69	—	—	—
A42MX09	—	—	72	83	95	101	—	—	—	83	104	—
A42MX16	—	—	72	83	—	125	140	—	—	83	140	—
A42MX24	—	—	72	—	—	125	176	—	—	—	150	—
A42MX36	—	—	—	—	—	—	176	202	—	—	—	202

Note: **Package Definitions:** PLCC = Plastic Leaded Chip Carrier, PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, VQFP = Very Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array

2.5 Ceramic Device Resources

Table 3 • Ceramic Device Resources

Device	User I/Os			
	CPGA 132-Pin	CQFP 172-Pin	CQFP 208-Pin	CQFP 256-Pin
A42MX09	95			
A42MX16		131		
A42MX36			176	202

Note: **Package Definitions:** CQFP = Ceramic Quad Flat Pack

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

Figure 14 • 42MX IEEE 1149.1 Boundary Scan Circuitry

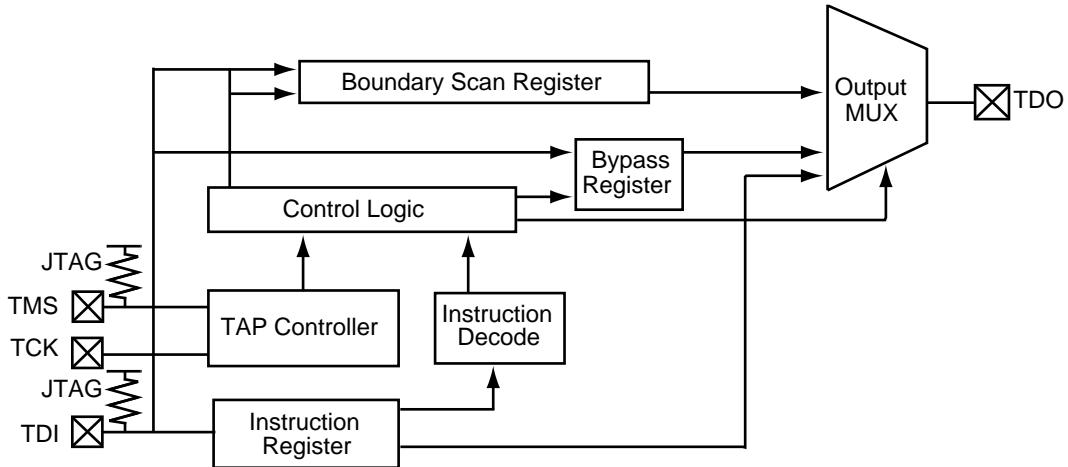


Table 9 • Test Access Port Descriptions

Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

Table 10 • Supported BST Public Instructions

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

3.4.9 JTAG Mode Activation

The JTAG test logic circuit is activated in the Designer software by selecting **Tools > Device Selection**. This brings up the Device Selection dialog box as shown in the following figure. The JTAG test logic circuit can be enabled by clicking the “Reserve JTAG Pins” check box. The following table explains the pins’ behavior in either mode.

Figure 15 • Device Selection Wizard

Table 11 • Boundary Scan Pin Configuration and Functionality

Reserve JTAG	Checked	Unchecked
TCK	BST input; must be terminated to logical HIGH or LOW to avoid floating	User I/O
TDI, TMS	BST input; may float or be tied to HIGH	User I/O
TDO	BST output; may float or be connected to TDI of another device	User I/O

3.4.10 TRST Pin and TAP Controller Reset

An active reset (TRST) pin is not supported; however, MX devices contain power-on circuitry that resets the boundary scan circuitry upon power-up. Also, the TMS pin is equipped with an internal pull-up resistor. This allows the TAP controller to remain in or return to the Test-Logic-Reset state when there is no input or when a logical 1 is on the TMS pin. To reset the controller, TMS must be HIGH for at least five TCK cycles.

3.4.11 Boundary Scan Description Language (BSDL) File

Conforming to the IEEE Standard 1149.1 requires that the operation of the various JTAG components be documented. The BSDL file provides the standard format to describe the JTAG components that can be used by automatic test equipment software. The file includes the instructions that are supported, instruction bit pattern, and the boundary-scan chain order. For an in-depth discussion on BSDL files, see the *BSDL Files Format Description* application note.

BSDL files are grouped into two categories - generic and device-specific. The generic files assign all user I/Os as inouts. Device-specific files assign user I/Os as inputs, outputs or inouts.

Generic files for MX devices are available on the Microsemi SoC Product Group's website:

<http://www.microsemi.com/soc/techdocs/models/bsdl.html>.

3.5 Development Tool Support

The MX family of FPGAs is fully supported by Libero® Integrated Design Environment (IDE). Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes SynplifyPro from Synopsys, ModelSim® HDL Simulator from Mentor Graphics® and Viewdraw.

Libero IDE includes place-and-route and provides a comprehensive suite of backend support tools for FPGA development, including timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor.

3.8.1 3.3 V LVTTL Electrical Specifications

Table 19 • 3.3V LVTTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = -4 mA	2.15		2.15		2.4		2.4		V
VOL ¹	IOL = 6 mA		0.4		0.4		0.48		0.48	V
VIL		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX)		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL			-10		-10		-10		-10	µA
IIH			-10		-10		-10		-10	µA
Input Transition Time, T _R and T _F			500		500		500		500	ns
C _{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC ²	A40MX02, A40MX04	3		25		10		25		mA
	A42MX09	5		25		25		25		mA
	A42MX16	6		25		25		25		mA
	A42MX24, A42MX36	15		25		25		25		mA
Low-Power Mode Standby Current	42MX devices only	0.5		ICC - 5.0		ICC - 5.0		ICC - 5.0		mA
IIO, I/O source sink current	Can be derived from the <i>IB/S model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min.
2. All outputs unloaded. All inputs = VCC/VCCI or GND.

3.9 Mixed 5.0 V / 3.3 V Operating Conditions (for 42MX Devices Only)

Table 20 • Absolute Maximum Ratings*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	-0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCCA + 0.5	V
VO	Output Voltage	-0.5 to VCCI + 0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (\text{°C}) - \text{Max} \cdot \text{ambient temp} \cdot (\text{°C})}{\theta_{ja}(\text{°C/W})} = \frac{150\text{°C} - 70\text{°C}}{(28\text{°C})/\text{W}} = 2.86\text{W}$$

EQ 5

The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (\text{°C}) - \text{Max} \cdot \text{ambient temp} \cdot (\text{°C})}{\theta_{jc}(\text{°C/W})} = \frac{150\text{°C} - 125\text{°C}}{(6.3\text{°C})/\text{W}} = 3.97\text{W}$$

EQ 6

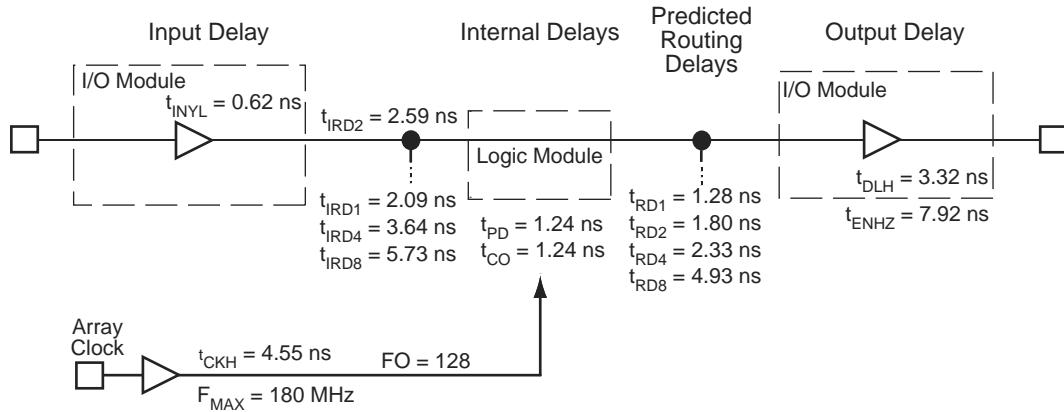
Table 27 • Package Thermal Characteristics

Plastic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min.	2.5 m/s 500 ft/min.	
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	°C/W
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	°C/W
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	°C/W
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	°C/W
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	°C/W
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	°C/W
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	°C/W
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	°C/W
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	°C/W
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	°C/W
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	°C/W
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	°C/W

3.10 Timing Models

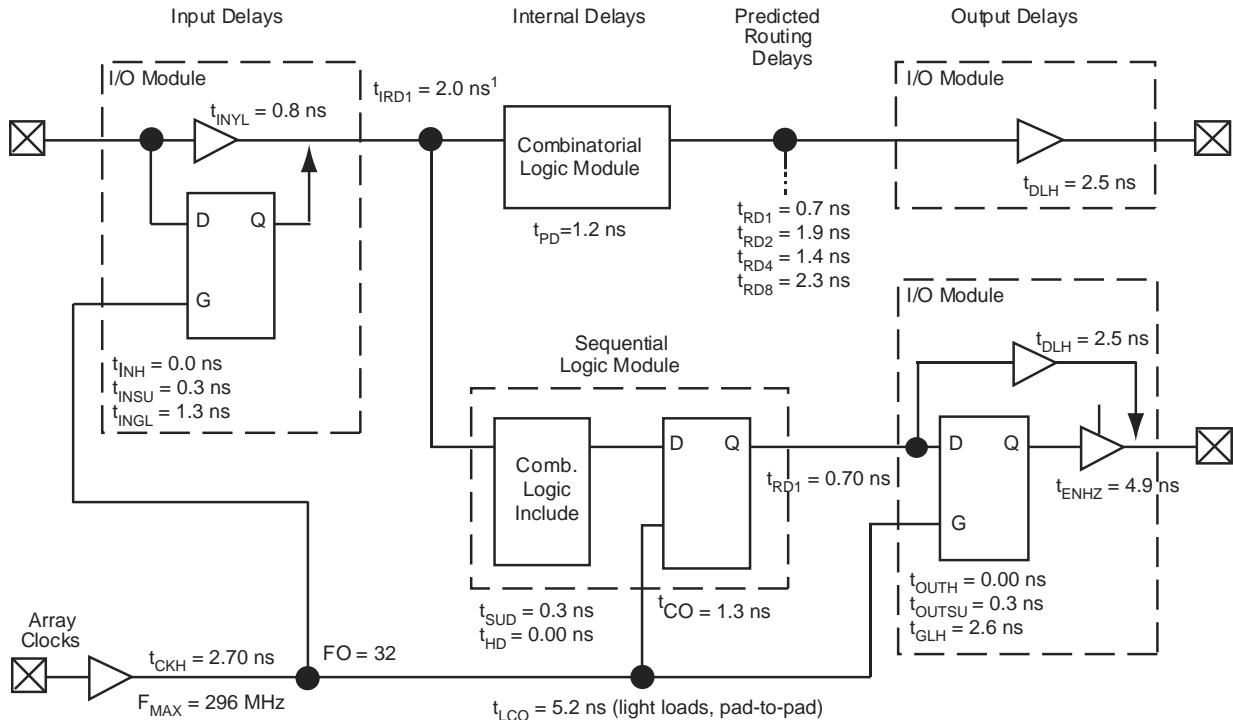
The following figures show various timing models.

Figure 17 • 40MX Timing Model*



Note: Values are shown for 40MX –3 speed devices at 5.0 V worst-case commercial conditions.

Figure 18 • 42MX Timing Model



Note: 1. Input module predicted routing delay

Note: 2. Values are shown for A42MX09 –3 at 5.0 V worst-case commercial conditions.

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, TJ = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.5		4.9		5.6		6.6		9.2		ns
t _A	Flip-Flop Clock Input Period	3.5		3.8		4.3		5.1		7.1		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency	268		244		224		195		117		MHz

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing⁵											
t _{DH}	Data-to-Pad HIGH	2.5	2.7	3.1	3.6	5.1	ns				
t _{DHL}	Data-to-Pad LOW	2.9	3.2	3.6	4.3	6.0	ns				
t _{ENZH}	Enable Pad Z to HIGH	2.6	2.9	3.3	3.9	5.5	ns				
t _{ENZL}	Enable Pad Z to LOW	2.9	3.2	3.7	4.3	6.1	ns				
t _{ENHZ}	Enable Pad HIGH to Z	4.9	5.4	6.2	7.3	10.2	ns				
t _{ENLZ}	Enable Pad LOW to Z	5.3	5.9	6.7	7.9	11.1	ns				
t _{GLH}	G-to-Pad HIGH	2.6	2.9	3.3	3.8	5.3	ns				
t _{GHL}	G-to-Pad LOW	2.6	2.9	3.3	3.8	5.3	ns				
t _{LSU}	I/O Latch Set-Up	0.5	0.5	0.6	0.7	1.0	ns				
t _{LH}	I/O Latch Hold	0.0	0.0	0.0	0.0	0.0	ns				
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading	5.2	5.8	6.6	7.7	10.8	ns				
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading	7.4	8.2	9.3	10.9	15.3	ns				
d _{TLH}	Capacity Loading, LOW to HIGH	0.03	0.03	0.03	0.04	0.06	ns/pF				
d _{THL}	Capacity Loading, HIGH to LOW	0.04	0.04	0.04	0.05	0.07	ns/pF				

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, TJ = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD4}	FO = 4 Routing Delay			1.9		2.1		2.4		2.9		4.0 ns
t _{RD8}	FO = 8 Routing Delay			3.2		3.6		4.1		4.8		6.7 ns
Logic Module Sequential Timing^{3, 4}												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.5		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.7		5.3		6.0		7.0		9.8	ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.2		6.9		7.8		9.2		12.9	ns
t _A	Flip-Flop Clock Input Period	5.0		5.6		6.2		7.1		9.9		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{NSU}	Input Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		161		146		135		117		70	MHz

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, TJ = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Sequential Timing^{3, 4}											
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.5	0.5	0.6	0.7	0.9					ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0	0.0	0.0	0.0	0.0					ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	1.0	1.1	1.2	1.4	2.0					ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0					ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.8	5.3	6.0	7.1	9.9					ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	6.2	6.9	7.9	9.2	12.9					ns
t _A	Flip-Flop Clock Input Period	9.5	10.6	12.0	14.1	19.8					ns
t _{IINH}	Input Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0					ns
t _{INSU}	Input Buffer Latch Set-Up	0.7	0.8	0.9	1.01	1.4					ns
t _{OUTH}	Output Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0					ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.7	0.8	0.89	1.01	1.4					ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency	129	117	108	94	56	MHz				
Input Module Propagation Delays											
t _{IINYH}	Pad-to-Y HIGH	1.5	1.6	1.9	2.2	3.1	ns				
t _{IINYL}	Pad-to-Y LOW	1.1	1.3	1.4	1.7	2.4	ns				
t _{INGH}	G to Y HIGH	2.0	2.2	2.5	2.9	4.1	ns				
t _{INGL}	G to Y LOW	2.0	2.2	2.5	2.9	4.1	ns				
Input Module Predicted Routing Delays²											
t _{IRD1}	FO = 1 Routing Delay	2.6	2.9	3.2	3.8	5.3	ns				
t _{IRD2}	FO = 2 Routing Delay	2.9	3.2	3.7	4.3	6.1	ns				
t _{IRD3}	FO = 3 Routing Delay	3.3	3.6	4.1	4.9	6.8	ns				
t _{IRD4}	FO = 4 Routing Delay	3.6	4.0	4.6	5.4	7.6	ns				
t _{IRD8}	FO = 8 Routing Delay	5.1	5.6	6.4	7.5	10.5	ns				
Global Clock Network											
t _{CKH}	Input LOW to HIGH	FO = 32	4.4	4.8	5.5	6.5	9.0	ns			
		FO = 384	4.8	5.3	6.0	7.1	9.9	ns			
t _{CKL}	Input HIGH to LOW	FO = 32	5.3	5.9	6.7	7.8	11.0	ns			
		FO = 384	6.2	6.9	7.9	9.2	12.9	ns			
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	5.7	6.3	7.1	8.4	11.8	ns			
		FO = 384	6.6	7.4	8.3	9.8	13.7	ns			

4 Package Pin Assignments

The following figures and tables give the details of the package pin assignments.

Figure 38 • PL44

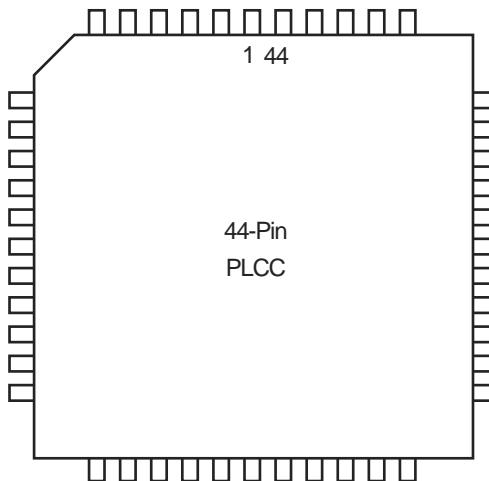


Table 47 • PL44

PL44		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	I/O	I/O
3	VCC	VCC
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	I/O	I/O
8	I/O	I/O
9	I/O	I/O
10	GND	GND
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	VCC	VCC
15	I/O	I/O
16	VCC	VCC
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	I/O	I/O

Table 53 • PQ208

PQ208	Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
	58	I/O	WD, I/O	WD, I/O
	59	I/O	I/O	I/O
	60	VCCI	VCCI	VCCI
	61	NC	I/O	I/O
	62	NC	I/O	I/O
	63	I/O	I/O	I/O
	64	I/O	I/O	I/O
	65	I/O	I/O	QCLKA, I/O
	66	I/O	WD, I/O	WD, I/O
	67	NC	WD, I/O	WD, I/O
	68	NC	I/O	I/O
	69	I/O	I/O	I/O
	70	I/O	WD, I/O	WD, I/O
	71	I/O	WD, I/O	WD, I/O
	72	I/O	I/O	I/O
	73	I/O	I/O	I/O
	74	I/O	I/O	I/O
	75	I/O	I/O	I/O
	76	I/O	I/O	I/O
	77	I/O	I/O	I/O
	78	GND	GND	GND
	79	VCCA	VCCA	VCCA
	80	NC	VCCI	VCCI
	81	I/O	I/O	I/O
	82	I/O	I/O	I/O
	83	I/O	I/O	I/O
	84	I/O	I/O	I/O
	85	I/O	WD, I/O	WD, I/O
	86	I/O	WD, I/O	WD, I/O
	87	I/O	I/O	I/O
	88	I/O	I/O	I/O
	89	NC	I/O	I/O
	90	NC	I/O	I/O
	91	I/O	I/O	QCLKB, I/O
	92	I/O	I/O	I/O
	93	I/O	WD, I/O	WD, I/O
	94	I/O	WD, I/O	WD, I/O

Table 53 • PQ208

PQ208	Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
	132	VCCI	VCCI	VCCI
	133	VCCA	VCCA	VCCA
	134	I/O	I/O	I/O
	135	I/O	I/O	I/O
	136	VCCA	VCCA	VCCA
	137	I/O	I/O	I/O
	138	I/O	I/O	I/O
	139	I/O	I/O	I/O
	140	I/O	I/O	I/O
	141	NC	I/O	I/O
	142	I/O	I/O	I/O
	143	I/O	I/O	I/O
	144	I/O	I/O	I/O
	145	I/O	I/O	I/O
	146	NC	I/O	I/O
	147	NC	I/O	I/O
	148	NC	I/O	I/O
	149	NC	I/O	I/O
	150	GND	GND	GND
	151	I/O	I/O	I/O
	152	I/O	I/O	I/O
	153	I/O	I/O	I/O
	154	I/O	I/O	I/O
	155	I/O	I/O	I/O
	156	I/O	I/O	I/O
	157	GND	GND	GND
	158	I/O	I/O	I/O
	159	SDI, I/O	SDI, I/O	SDI, I/O
	160	I/O	I/O	I/O
	161	I/O	WD, I/O	WD, I/O
	162	I/O	WD, I/O	WD, I/O
	163	I/O	I/O	I/O
	164	VCCI	VCCI	VCCI
	165	NC	I/O	I/O
	166	NC	I/O	I/O
	167	I/O	I/O	I/O
	168	I/O	WD, I/O	WD, I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
52	VCCI
53	I/O
54	WD, I/O
55	WD, I/O
56	I/O
57	SDI, I/O
58	I/O
59	VCCA
60	GND
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	VCCI
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	VCCA
86	I/O
87	I/O
88	VCCA

Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
37	I/O
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	I/O
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	GND
53	GND
54	TMS, I/O
55	TDI, I/O
56	I/O
57	WD, I/O
58	WD, I/O
59	I/O
60	VCCI
61	I/O
62	I/O
63	I/O
64	I/O
65	QCLKA, I/O
66	WD, I/O
67	WD, I/O
68	I/O
69	I/O
70	WD, I/O
71	WD, I/O
72	I/O
73	I/O

Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
185	I/O
186	CLKB, I/O
187	I/O
188	PRB, I/O
189	I/O
190	WD, I/O
191	WD, I/O
192	I/O
193	I/O
194	WD, I/O
195	WD, I/O
196	QCLKC, I/O
197	I/O
198	I/O
199	I/O
200	I/O
201	I/O
202	VCCI
203	WD, I/O
204	WD, I/O
205	I/O
206	I/O
207	DCLK, I/O
208	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
96	VCCA
97	GND
98	GND
99	I/O
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	WD, I/O
106	WD, I/O
107	I/O
108	I/O
109	WD, I/O
110	WD, I/O
111	I/O
112	QCLKA, I/O
113	I/O
114	GND
115	I/O
116	I/O
117	I/O
118	I/O
119	VCCI
120	I/O
121	WD, I/O
122	WD, I/O
123	I/O
124	I/O
125	I/O
126	I/O
127	GND
128	NC
129	NC
130	NC
131	GND
132	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
133	I/O
134	I/O
135	I/O
136	I/O
137	I/O
138	I/O
139	GND
140	I/O
141	I/O
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	I/O
149	I/O
150	I/O
151	I/O
152	I/O
153	I/O
154	I/O
155	VCCA
156	I/O
157	I/O
158	VCCA
159	VCCI
160	GND
161	I/O
162	I/O
163	I/O
164	I/O
165	GND
166	I/O
167	I/O
168	I/O
169	I/O

Table 61 • PG132

PG132	
Pin Number	A42MX09 Function
B3	I/O
A2	I/O
C3	DCLK
B5	GNDA
E12	GNDA
J2	GNDA
M9	GNDA
B9	GNDI
C5	GNDI
E11	GNDI
F4	GNDI
J3	GNDI
J11	GNDI
L5	GNDI
L9	GNDI
C9	GNDQ
E3	GNDQ
K12	GNDQ
D7	VCCA
G3	VCCA
G10	VCCA
L7	VCCA
C7	VCCI
G2	VCCI
G11	VCCI
K7	VCCI